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\*\* CONTINUING DATA \*\*\*\*\* *note* *gib*\*\* FOREIGN APPLICATIONS \*\*\*\*\* *gib*

JAPAN 2000-193104 06/27/2000  
JAPAN 2000-229101 07/28/2000  
JAPAN 2000-335934 11/02/2000  
JAPAN 2001-11218 01/19/2001  
JAPAN 2001-31901 02/08/2001  
JAPAN 2001-31906 02/08/2001  
JAPAN 2001-33599 02/09/2001  
JAPAN 2001-35089 02/13/2001  
JAPAN 2001-158662 05/28/2001  
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35 USC 119 (e-d) conditions met	<input checked="" type="checkbox"/> yes <input type="checkbox"/> no <input type="checkbox"/> Not after	JAPAN	50	60	13
Verified and Acknowledged	Advantage <i>gib</i> Examiner's Signature				

ADDRESS

23850

TITLE

Inspection system by charged particle beam and method of manufacturing devices using the system